

Search Notes

Application/Control No.

10/672,381

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2673

SEARCHED

Class	Subclass	Date	Examiner
345	426	9/18/2005	PN
	427	9/18/2005	PN
	428	9/18/2005	PN
	419	9/18/2005	PN
	423	9/18/2005	PN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST search (BRDF, matrix, light, view, normal, reflectivity)	9/18/2005	PN
IEEE, ACM search (BRDF, matrix, light, view, normal, reflectivity)	9/18/2005	PN
Inventor Name search	9/18/2005	PN